

**A CONTACT SPRING FOR A TESTING BASE
FOR THE HIGH CURRENT TESTING OF AN
ELECTRONIC COMPONENT**

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ABSTRACT

A contact spring for a testing base for the current testing, in particular high current testing, of an electronic component, which is produced from a spring metal sheet of a predetermined thickness and possesses two, in particular identical, opposing lateral faces, and which has a spring arm and a testing arm with a testing tip, wherein the testing arm forms an angle with the spring arm, which enables the testing tip to be positioned on a contact surface of the electronic component running approximately parallel to the spring arm, by means of a relative movement between the testing base and the electronic component, wherein the geometry of the lateral faces fulfils the following conditions:

- a dimension of the distance between the first point and a second point is at least 2.3 times a length
- the first point is located on the boundary line of the lateral face facing towards the electronic component, and comprises a distance from the testing tip of 3 to 5 times, in particular 4 times, the length
- the first point forms the apex of an angle in a range between 120° and 150°, in particular of a 135° angle, the one leg of which extends in the direction of the relative movement between the testing base and the electronic component towards the electronic component, and the other leg of which cuts the boundary line of the lateral face facing away from the electronic component at the second point
- the length corresponds to the minimum thickness of the spring arm, as viewed in the direction of the relative movement between testing base and electronic component.

Fig. 3